64M x 72 1 Bank Registered/Buffered SDRAM Module

Features

- 168-Pin Registered 8-Byte Dual In-Line Memory Module
- 64Mx72 Synchronous DRAM DIMM
- Performance:

			-260 CL=2		-360 CL=3		-360 CL=2	
		Reg.	Buff.	Reg.	Buff	Reg.	Buff.	UIIIIS
DIMM CAS Latency		3	2	4	3	3	2	
f_{CK}	Clock Frequency	100	100	100	100	66	66	MHz
f_{CK}	Clock Cycle	10	10	10	10	15	15	ns
t_{AC}	Clock Access	7.2	7.2	7.2	7.2	10.2	10.2	ns

- Intended for 66/100MHz and PC100 applications
- Inputs and outputs are LVTTL (3.3V) compatible
- Single 3.3V ± 0.3V Power Supply
- Single Pulsed RAS interface
- SDRAMs have four internal banks
- Module has one physical bank

- Fully Synchronous to positive Clock Edge
- Programmable Operation:
 - DIMM CAS Latency: 3, 4 (Registered mode); 2, 3 (Buffered mode)
 - Burst Type: Sequential or Interleave
 - Burst Length: 1, 2, 4, 8
 - Operation: Burst Read and Write or Multiple Burst Read with Single Write
- Data Mask for Byte Read/Write control
- Auto Refresh (CBR) and Self Refresh
- Automatic and controlled Precharge Commands
- Suspend Mode and Power Down Mode
- 13/11/2 Addressing (Row/Column/Bank)
- 8192 refresh cycles distributed across 64ms
- Card size: 5.25" x 1.70" x 0.157"
- Gold contacts
- SDRAMs in TSOP Type II Package
- Serial Presence Detect with Write protect

Description

IBM13M64734BCA is a registered 168-Pin Synchronous DRAM Dual-In-Line Memory Module (DIMM) organized as a 64Mx72 high-speed memory array. The DIMM uses eighteen 64Mx4 SDRAMs in 400 mil TSOP packages. The DIMM achieves high-speed data-transfer rates of up to 100 MHz by employing a prefetch/pipeline hybrid architecture that synchronizes the output data to a system clock.

The DIMM is intended for use in applications operating from 66MHz to 100 MHz, PC100, memory bus speeds, and/or heavily loaded bus applications. All control and address signals are re-driven through registers/buffers to the SDRAM devices. The DIMM can be operated in either registered mode (REGE pin tied high), where the control/address input signals are latched in the register on one rising clock edge and sent to the SDRAM devices on the following rising clock edge (data access is delayed by one clock), or in buffered mode (REGE pin tied low), where the input signals pass through the register/buffer to the SDRAM devices on the same clock. XTK simulation models of the DIMM are available to determine which mode to design for.

A phase-lock loop (PLL) on the DIMM is used to redrive the clock signals to both the SDRAM devices and the registers to minimize system clock loading. (CK0 is connected to the PLL, and CK1, CK2, and CK3 are terminated on the DIMM.) A single clock enable (CKE0) controls all devices on the DIMM, enabling the use of SDRAM power-down modes.

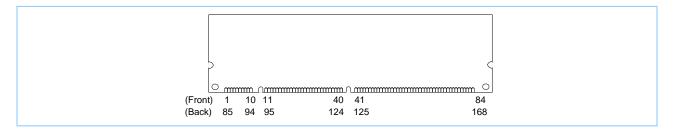
Prior to any access operation, the device $\overline{\text{CAS}}$ latency and burst type/length/operation type must be programmed into the DIMM by address inputs A0-A9 using the mode register set cycle. The DIMM $\overline{\text{CAS}}$ latency when operated in buffered mode is the same as the device $\overline{\text{CAS}}$ latency as specified in the SPD EEPROM. The DIMM $\overline{\text{CAS}}$ latency when operated in registered mode is one clock later due to the address and control signals being clocked to the SDRAM devices.

The DIMM uses serial presence detects implemented via a serial EEPROM using the two-pin IIC protocol. The first 128 bytes of serial PD data are programmed and locked by the DIMM manufacturer. The last 128 bytes are available to the customer and may be write protected by providing a high level to pin 81 on the DIMM. (An on-board pull-down resistor keeps this in the write-enable mode.)

All IBM 168-pin DIMMs provide a high-performance, flexible 8-byte interface in a 5.25" long space-saving footprint.



Card Outline



Pin Description

CK0 - CK3	Clock Inputs	DQ0 - DQ63	Data Input/Output
CKE0	Clock Enable	CB0 - CB7	Check Bit Data Input/Output
RAS	Row Address Strobe	DQMB0 - DQMB7	Data Mask
CAS	Column Address Strobe	V_{DD}	Power (3.3V)
WE	Write Enable	V _{SS}	Ground
<u>\$</u> 0, <u>\$</u> 2	Chip Selects	NC	No Connect
A0 - A9, A11, A12	Address Inputs	SCL	Serial Presence Detect Clock Input
A10/AP	Address Input/Autoprecharge	SDA	Serial Presence Detect Data Input/Output
BA0, BA1	SDRAM Bank Address Inputs	SA0-2	Serial Presence Detect Address Inputs
WP	SPD Write Protect	REGE	Register Enable

Pinout

Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side
1	V _{SS}	85	V _{SS}	22	CB1	106	CB5	43	V _{SS}	127	V _{SS}	64	V _{SS}	148	V _{SS}
2	DQ0	86	DQ32	23	V_{SS}	107	V_{SS}	44	NC	128	CKE0	65	DQ21	149	DQ53
3	DQ1	87	DQ33	24	NC	108	NC	45	S 2	129	NC	66	DQ22	150	DQ54
4	DQ2	88	DQ34	25	NC	109	NC	46	DQMB2	130	DQMB6	67	DQ23	151	DQ55
5	DQ3	89	DQ35	26	V_{DD}	110	V_{DD}	47	DQMB3	131	DQMB7	68	V_{SS}	152	V_{SS}
6	V_{DD}	90	V_{DD}	27	WE	111	CAS	48	NC	132	NC	69	DQ24	153	DQ56
7	DQ4	91	DQ36	28	DQMB0	112	DQMB4	49	V_{DD}	133	V_{DD}	70	DQ25	154	DQ57
8	DQ5	92	DQ37	29	DQMB1	113	DQMB5	50	NC	134	NC	71	DQ26	155	DQ58
9	DQ6	93	DQ38	30	S 0	114	NC	51	NC	135	NC	72	DQ27	156	DQ59
10	DQ7	94	DQ39	31	NC	115	RAS	52	CB2	136	CB6	73	V_{DD}	157	V_{DD}
11	DQ8	95	DQ40	32	V_{SS}	116	V_{SS}	53	CB3	137	CB7	74	DQ28	158	DQ60
12	V_{SS}	96	V_{SS}	33	A0	117	A1	54	V_{SS}	138	V_{SS}	75	DQ29	159	DQ61
13	DQ9	97	DQ41	34	A2	118	А3	55	DQ16	139	DQ48	76	DQ30	160	DQ62
14	DQ10	98	DQ42	35	A4	119	A5	56	DQ17	140	DQ49	77	DQ31	161	DQ63
15	DQ11	99	DQ43	36	A6	120	A7	57	DQ18	141	DQ50	78	V_{SS}	162	V_{SS}
16	DQ12	100	DQ44	37	A8	121	A9	58	DQ19	142	DQ51	79	CK2	163	CK3
17	DQ13	101	DQ45	38	A10/AP	122	BA0	59	V_{DD}	143	V_{DD}	80	NC	164	NC
18	V_{DD}	102	V_{DD}	39	BA1	123	A11	60	DQ20	144	DQ52	81	WP	165	SA0
19	DQ14	103	DQ46	40	V_{DD}	124	V_{DD}	61	NC	145	NC	82	SDA	166	SA1
20	DQ15	104	DQ47	41	V_{DD}	125	CK1	62	NC	146	NC	83	SCL	167	SA2
21	CB0	105	CB4	42	CK0	126	A12	63	NC	147	REGE	84	V_{DD}	168	V_{DD}
Note:	All pin a	ssignm	ents are o	consiste	ent with all	8-byte	unbuffere	d versi	ons.						

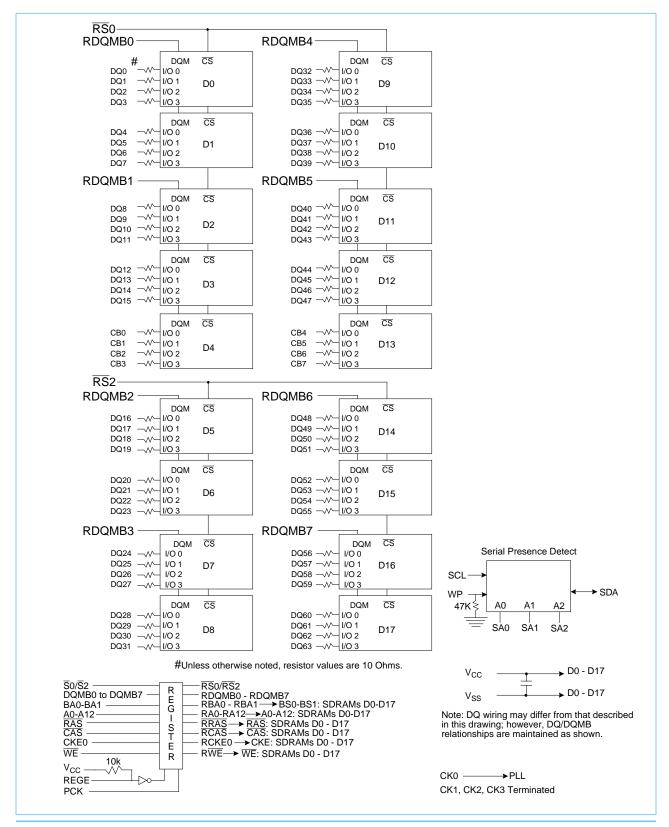


Ordering Information

Part Number	Organization	D <u>evic</u> e CAS Latency	Device Access Time	Clock Cycle	Leads	Dimension	Power	Note
IBM13M64734BCA-260T	64Mx72	3	6ns	10ns				_
IBM13M64734BCA-360T	0.41470	3	6ns	10ns	Gold	5.25" x 0.157" x 1.70"	3.3V	1
IDIVI131V104734DCA-3001	64Mx72	2	9ns	15ns				
PC100 applications								

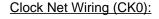


x72 ECC SDRAM DIMM Block Diagram (1 Bank, x4 SDRAMs)

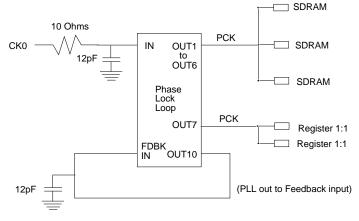




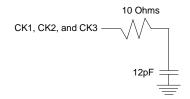
Clock Wiring



One of six SDRAM outputs is shown. All PLL clock SDRAM loads are equal-achieved in part through equal-length wiring.



Terminated Clock Nets (CK1, CK2, CK3):



- Notes: 1. The PLL is programmed via a combination of the feedback path and on-DIMM loading. PLL feedback produces zero phase shift from the delayed CK0 input.
 - 2. Card wiring and capacitance loading variation: \pm 100 ps.
 - 3. Timing is based on a driver with a 1 Volt/ns rise time.



Input/Output Functional Description

Symbol	Type	Signal	Polarity	Function
CK0 - CK3	Input	Pulse	Positive Edge	The system clock inputs. All the SDRAM inputs are sampled on the rising edge of their associated clock. CK0 drives the PLL. CK1, CK2, and CK3 are terminated.
CKE0	Input	Level	Active High	Activates the SDRAM CK signal when high and deactivates the CK signal when low. By deactivating the clocks, CKE low initiates the Power Down mode, the Suspend mode, or the Self Refresh mode.
<u>\$</u> 0, <u>\$</u> 2	Input	Pulse	Active Low	Enables the associated SDRAM command decoder when low and disables the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue.
RAS, CAS WE	Input	Pulse	Active Low	When sampled at the positive rising edge of the clock, $\overline{\text{CAS}}$, $\overline{\text{RAS}}$, and $\overline{\text{WE}}$ define the operation to be executed by the SDRAM.
BA0, 1	Input	Level	_	Selects which SDRAM bank of four is activated.
A0 - A9, A11, A12 10/AP	Input	Level	_	During a Bank Activate command cycle, A0-A12 defines the row address (RA0-RA12) when sampled at the rising clock edge. During a Read or Write command cycle, A0-A9, A11 defines the column address (CA0-CA9, A11) when sampled at the rising clock edge. In addition to the column address, AP is used to invoke autoprecharge operation at the end of the burst read or write cycle. If AP is high, autoprecharge is selected and BA0, BA1 defines the bank to be precharged. If AP is low, autoprecharge is disabled. During a Precharge command cycle, AP is used in conjunction with BA0, BA1 to control which bank(s) to precharge. If AP is high, all banks will be precharged regardless of the state of BA0 or BA1. If AP is low, BA0 and BA1 are used to define which bank to precharge.
DQ0 - DQ63, CB0 - CB7	Input Output	Level	_	Data and Check Bit Input/Output pins
DQMB0 - DQMB7	Input	Pulse	Active High	The Data Input/Output masks, associated with one data byte, place the DQ buffers in a high-impedance state when sampled high. In Read mode, DQMB has a latency of two clock cycles in Buffered mode or three clock cycles in Registered mode, and controls the output buffers like an output enable. In Write mode, DQMB has a zero clock latency in Buffered mode and a latency of one clock cycle in Registered mode. In this case, DQMB operates as a byte mask by allowing input data to be written if it is low but blocking the write operation if it is high.
V_{DD} , V_{SS}	Supply			Power and ground for the module.
REGE	Input	Level	Active High (Register Mode Enable)	The Register Enable pin is used to permit the DIMM to operate in "buffered" mode (inputs re-driven asynchronously) or "registered" mode (signals re-driven to SDRAMs when clock rises, and held valid until next rising clock).
SA0 - 2	Input	Level	_	These signals are tied at the system planar to either V_{SS} or V_{DD} to configure the serial SPD EEPROM.
SDA	Input Output	Level	_	This bidirectional pin is used to transfer data into or out of the SPD EEPROM. A resistor must be connected from the SDA bus line to V_{DD} to act as a pullup.
SCL	Input	Pulse	_	This signal is used to clock data into and out of the SPD EEPROM. A resistor may be connected from the SCL bus time to $V_{\rm DD}$ to act as a pullup.
WP	Input	Level	Active High	This signal is pulled low on the DIMM to enable data to be written into the last 128 bytes of the SPD EEPROM.



Serial Presence Detect (Part 1 of 2)

Byte #	Description		SPD Entry Value	Serial PD Data Entry (Hexadecimal)	Notes
0	Number of Serial PD Bytes Written duri	ing Production	128	80	
1	Total Number of Bytes in Serial PD dev	vice	256	08	
2	Fundamental Memory Type		SDRAM	04	
3	Number of Row Addresses on Assemb	ly	13	0D	
4	Number of Column Addresses on Asse	embly	11	0B	
5	Number of DIMM Banks		1	01	
6 - 7	Data Width of Assembly		x72	4800	
8	Assembly Voltage Interface Levels		LVTTL	01	
9	SDRAM Device Cycle Time (CL = 3)		10ns	10	1, 2
10	SDRAM Device Access Time from Clock at CL=3	-260	6.0ns	60	
11	Assembly Error Detection/Correction S	cheme	ECC	02	
12	Assembly Refresh Rate/Type		SR/1X(7.813us)	82	
13	SDRAM Device Width		x4	04	
14	Error Checking SDRAM Device Width	Error Checking SDRAM Device Width		04	
15	SDRAM Device Attr: Min Clk Delay, Ra Access	SDRAM Device Attr: Min Clk Delay, Random Col Access		01	
16	SDRAM Device Attributes: Burst Lengtl	hs Supported	1,2,4,8	0F	
17	SDRAM Device Attributes: Number of D	Device Banks	4	04	
18	SDRAM Device Attributes: CAS Latence	у	2, 3	06	
19	SDRAM Device Attributes: CS Latency		0	01	
20	SDRAM Device Attributes: WE Latency	/	0	01	
21	SDRAM Module Attributes		Registered/Buffered with PLL	IF	
22	SDRAM Device Attributes: General		Write-1/Read Burst, Pre- charge All, Auto-Precharge	0E	
23	Minimum Clock Cycle at CLX-1 (CL =	-260	10.0ns	A0	1,2
20	2)	-360	15.0ns	F0	1,∠
24	Maximum Data Access Time (t _{AC}) -260		6.0ns	60	
	from Clock at CLX-1 (CL = 2)	om Clock at CLX-1 (CL = 2) -360		90	
25	Minimum Clock Cycle Time at CLX-2 (0	CL = 1)	N/A	00	
26	Maximum Data Access Time (t_{AC}) from $(CL = 1)$	Clock at CLX-2	N/A	00	
27	Minimum Row Precharge Time (t _{RP})		20.0ns	14	

^{1.} In a registered DIMM, data is delayed an additional clock cycle due to the on-DIMM pipeline register (i.e., Device CL [clock cycles] + 1 = DIMM CAS latency).

^{2.} Minimum application clock cycle time for the -360 is 10ns (100MHz).

^{3.} cc = Checksum Data byte, 00-FF (Hex)

^{4. &}quot;R" = Alphanumeric revision code, A-Z, 0-9

^{5.} rr = ASCII coded revision code byte "R"

^{6.} ww = Binary coded decimal week code, 01-52 (Decimal) → 01-34 (Hex)

^{7.} yy = Binary coded decimal year code, 00-99 (Decimal) → 00-63 (Hex)

^{8.} ss = Serial number data byte, 00-FF (Hex)



Serial Presence Detect (Part 2 of 2)

Byte #	Description		SPD Entry Value	Serial PD Data Entry (Hexadecimal)	Notes
28	Minimum Row Active to Row Active del	ay (t _{RRD})	20.0ns	14	
29	Minimum RAS to CAS delay (t _{RCD})		20.0ns	14	
30	Minimum RAS Pulse width (t _{RAS})		50.0ns	32	
31	Module Bank Density		512MB	80	
32	Address and Command Setup Time Be	fore Clock	2.0ns	20	
33	Address and Command Hold Time Afte	r Clock	1.0ns	10	
34	Data Input Setup Time Before Clock		2.0ns	20	
35	Data Input Hold Time After Clock		1.0ns	10	
36 - 61	Reserved		Undefined	00	
62	SPD Revision		PC100 1.2A	12	
63	Checksum for bytes 0 - 62		Checksum Data	СС	3
64 - 71	Manufacturers' JEDEC ID Code		IBM	A400000000000000	
70	A		Toronto, Canada	91	
72	Assembly Manufacturing Location		Vimercate, Italy	53	
70 00	Accomplete Death Neurobean	-260	ASCII '13M64734BC"R"- 260T'	31334D36343733344243rr 2D323630542020	
73 - 90	Assembly Part Number	-360	ASCII '13M64734BC"R"- 360T'	31334D36343733344243rr 2D333630542020	4, 5
91 - 92	Assembly Revision Code		"R" plus ASCII blank	rr20	5
93 - 94	Assembly Manufacturing Date		Year/Week Code	yyww	6, 7
95 - 98	Assembly Serial Number		Serial Number	SSSSSSS	8
99 - 125	Reserved		Undefined	Not Specified	
126	Module Supports this Clock Frequency		100MHz	64	
127	Attributes for clock frequency defined	-260	CLK0, CL=2,3, ConAP	87	
121	n Byte 126	-360	CLK0, CL=3, ConAP	85	
128 - 255	Open for Customer Use		Undefined	00	

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Absolute Maximum Ratings

Symbol	Parameter		Rating	Units	Notes
V_{DD}	Power Supply Voltage		-0.3 to +4.6		
		SDRAM Devices	-1.0 to +4.6		
V	Input Voltage	Serial PD Device	-0.3 to +6.5	1	
V _{IN}		Register	0 - V _{DD}	V	1
		-0.3 to +4.6 SDRAM Devices -1.0 to +4.6 Serial PD Device -0.3 to +6.5 Register 0 - V _{DD} PLL 0 - V _{DD} SDRAM Devices -1.0 to +4.6 Serial PD Device -0.3 to +6.5 (ambient) 0 to +70 -55 to +125 18 rent 50			
V	Power Supply Voltage Input Voltage Output Voltage Operating Temperature (ambient) Storage Temperature Power Dissipation Short Circuit Output Current	SDRAM Devices -1.0 to +4.6			
VOUT		Serial PD Device	-0.3 to +6.5		
T _A	Operating Temperature (ambient)		0 to +70	°C	1
T _{STG}	Storage Temperature		-55 to +125	°C	1
P _D	Power Dissipation		18	W	1, 2
I _{OUT}	Short Circuit Output Current		50	mA	1
F _{MIN}	Minimum Operating Frequency		66	MHz	

Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a
stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational
sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

^{2.} Maximum power is calculated assuming the physical bank is in Burst Operating Mode.



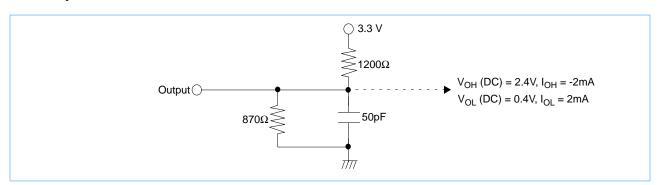
Recommended DC Operating Conditions $(T_A = 0 \text{ to } 70^{\circ}\text{C})$

Cumbal	Parameter		Rating	Units	Notes				
Symbol		Min.	Тур.	Max.	Units	Notes			
V_{DD}	Supply Voltage	3.0	3.3	3.6	V	1			
V_{IH}	Input High Voltage	2.0	_	V _{DD} + 0.3	V	1			
V _{IL}	Input Low Voltage	-0.3		0.8	V	1			
All voltages referenced to V _{SS} .									

Capacitance (T_A = 25°C, f=1MHz, V_{DD} = 3.3V 0.3V)

Symbol	Parameter	Max.	Units
C _{I1}	Input Capacitance (A0 - A9, A10/AP, BA0, BA1, A11, A12)	10.5	pF
C _{I2}	Input Capacitance (RAS)	10.0	pF
C _{I3}	Input Capacitance (CAS)	10.5	pF
C _{I4}	Input Capacitance (S0, S2)	11	pF
C _{I5}	Input Capacitance (CKE0)	20.5	pF
C _{I6}	Input Capacitance (CK0)	25	pF
C _{I7}	Input Capacitance (DQMB0 - DQMB7)	11	pF
C _{I8}	Input Capacitance (SA0 - SA2, SCL, WP)	9	pF
C _{I9}	Input Capacitance (REGE)	10	pF
C _{I10}	Input Capacitance (CK1 - CK3)	14	pF
C _{I11}	Input Capacitance (WE)	10	pF
C _{IO1}	Input/Output Capacitance (DQ0 - DQ63, CB0 - CB7)	11	pF
C _{IO2}	Input/Output Capacitance (SDA)	11	pF

DC Output Load Circuit





Input/Output Characteristics (T_A= 0 to +70 $^{\circ}\text{C}, \, \text{V}_{DD}\text{=} \, 3.3 \text{V} \pm 0.3 \text{V})$

Cumbal	Parameter			72	Units	Notes
Symbol	Parame	etei	Min.	Max.	Units	Notes
$I_{I(L)}$	Input Leakage Current, any input $(0.0V \le V_{IN} \le all$ other pins Not under test = 0V	ut Leakage Current, any input $(0.0V \le V_{\text{IN}} \le 3.6V)$, other pins Not under test = 0V				
la « ›	Output Leakage Current	DQ0-63, CB0 - 7	-2	+2	μА	
I _{O(L)}	$(D_{OUT} \text{ is disabled, } 0.0V \le V_{OUT} \le 3.6V)$	SDA	-1	+1	μΛ	
V _{OH}	Output Level Output "H" Level Voltage (I _{OUT} = -2.0mA)		2.4	V _{DD}	\/	4
V _{OL}	Output Level Output "L" Level Voltage (I _{OUT} = +2.0mA)		0.0	0.4	V	!



Operating, Standby, and Refresh Currents (T_A = 0 to +70°C, V_{DD} = 3.3V ±0.3V)

Doromotor	Cumhal	DIMM Operational Parameters	Clock	Cycle	Llaita	Notos
Parameter	Symbol	DIMM Operational Parameters	-10ns	-15ns	Units	Notes
Operating Current 1 bank operation	I _{CC1}	t _{RC} = t _{RC} (min), t _{CK} = min Active-Precharge command cycling without burst operation	2298	1760	mA	1, 2
Precharge Standby Current in	I _{CC2P}	$\begin{aligned} \text{CKE0} &\leq \text{V}_{\text{IL}}(\text{max}), \text{t}_{\text{CK}} = \text{min}, \\ \hline \text{CS} &= \text{V}_{\text{IH}} (\text{min}) \end{aligned}$	264	194	mA	1, 2
Power Down Modé	I _{CC2PS}	$\begin{aligned} \text{CKE0} &\leq \text{V}_{\text{IL}} (\text{max}), \text{t}_{\text{CK}} = \text{Infinity}, \\ &\overline{\text{S0}}, \overline{\text{S2}} = \text{V}_{\text{IH}} (\text{min}) \end{aligned}$	75	75	mA	
Precharge Standby Current in Non	I _{CC2N}	$\begin{aligned} \text{CKE0} &\geq \text{V}_{IH} \text{ (min), t}_{CK} = \text{min,} \\ &\overline{\text{S0}}, \overline{\text{S2}} = \text{V}_{IH} \text{ (min)} \end{aligned}$	588	518	mA	1, 2
Power Down Modé	I _{CC2NS}	$\begin{aligned} \text{CKE0} &\geq \text{V}_{IH} \text{ (min), t}_{CK} = \text{Infinity,} \\ &\overline{\text{S0}}, \overline{\text{S2}} = \text{V}_{IH} \text{ (min)} \end{aligned}$	147	147	mA	
No Operation Comment	I _{CC3N}	$\begin{aligned} \text{CKE0} &\geq \text{V}_{IH} \text{ (min), t}_{CK} = \text{min,} \\ &\overline{\text{S0}}, \overline{\text{S2}} = \text{V}_{IH} \text{ (min)} \end{aligned}$	1038	698	mA	1
No Operating Current (Active state: 4bank)	I _{CC3P}	$\begin{aligned} \text{CKE0} &\leq \text{V}_{\text{IL}} \text{ (max), t}_{\text{CK}} = \text{min,} \\ &\overline{\text{S0}}, \overline{\text{S2}} = \text{V}_{\text{IH}} \text{ (min)} \\ \text{(Power Down Mode)} \end{aligned}$	336	266	mA	1
Burst Operating Current (Active state: 4 bank)	I _{CC4}	t _{CK} = min, Read/Write command cycling Multiple banks active, Gapless date BL =4	2298	1544	mA	1, 2
Auto (CBR) Refresh Current	I _{CC5}	$t_{CK} = t_{CK}(min), t_{RC} = t_{RC} (min)$ CBR command cycling	3298	2534	mA	1
Self Refresh Current	I _{CC6}	CKE0 ≤ 0.2V	93	93	mA	

^{1.} These parameters depend on the cycle rate and are measured with the cycle determined by the minimum value of t_{CK} and t_{RC} . Input signals are changed once during t_{CK} (min).

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^{2.} The specified values are obtained with the DIMM data outputs open.

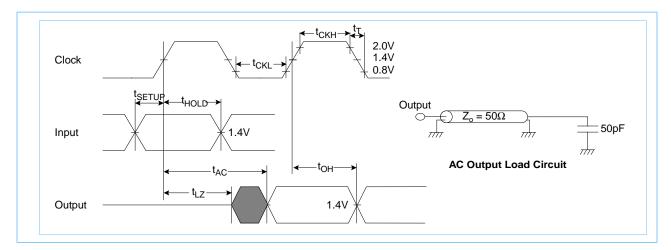
AC Characteristics (T_A = 0 to +70°C, V_{DD} = 3.3V \pm 0.3V)

- An initial pause of 200μs, with CKE0 held high, is required after power-up. A Precharge All Banks (logical, not physical) command must be given followed by a minimum of eight Auto (CBR) Refresh cycles before or after the Mode Register Set operation.
- 2. AC timing tests have $V_{IL} = 0.8V$ and $V_{IH} = 2.0V$ with the timing referenced to the 1.40V crossover point.

3

- 4. The Transition time is measured between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}).
- 5. AC measurements assume t_T=1.2ns (1 Volt/ns rise time).
- 6. In addition to meeting the transition rate specification, the clock and CKE must transit between V_{IH} and V_{IL} (or between V_{IL} and V_{IH}) in a monotonic manner.
- 7. A 1 ms stabilization time is required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal.

AC Output Load Circuits





Clock and Clock Enable Parameters

Symbol	mbol Parameter		Parameter		(Devid	max. ce CL, ,, t _{RP} 2, 2)	(Devidence)	max. ce CL, b, t _{RP} 2, 2)	Units	Notes
			Min.	Max.	Min.	Max.				
t _{CK4}	Clock Cycle Time, DIMM CAS Latency = 4	Registered	10	1000	10	1000	ns	1		
tour	Clock Cycle Time, DIMM CAS Latency = 3	Registered	10	1000	15	1000	ns	1		
t _{CK3}	Clock Cycle Time, Dilvilvi CAS Latericy = 3	Buffered	10	1000	10	1000	ns	1		
t _{CK2}	Clock Cycle Time, DIMM CAS Latency = 2	Buffered	10	1000	15	1000	ns	1		
t _{AC4}	Clock Access Time, DIMM CAS Latency = 4	Registered	_	7.2	_	7.2	ns	1, 2		
4	Cleak Access Time DIMM CAS Latency 2	Registered	_	7.2	_	10.2	ns	1, 2		
t _{AC3}	AC3 Clock Access Time, DIMM CAS Latency = 3	Buffered	_	7.2	_	7.2	ns	1, 2		
t _{AC2}	Clock Access Time, DIMM CAS Latency = 2	Buffered	_	7.2	_	10.2	ns	1, 2		
t _{CKH}	Clock High Pulse Width		3	_	3	_	ns	3		
t _{CKL}	Clock Low Pulse Width		3	_	3	_	ns	3		
t	Clock Fachla Catua Tima	Registered	2.0	_	2.0	_	ns	1		
t _{CES}	Clock Enable Setup Time	Buffered	7.2	_	7.2	_	ns	1		
toru	t Clash Fashia Hald Tires	Registered	1.0	_	1.0	_	ns	1		
t _{CEH}	Clock Enable Hold Time	Buffered	0.2	_	0.2	_	ns	l l		
t _{SB}	Power down mode Entry Time		0	10	0	10	ns			
t _T	Transition Time (Rise and Fall)		0.5	10	0.5	10	ns			

^{1.} DIMM $\overline{\text{CAS}}$ latency = device CL [clock cycles] + 1 for Register mode; DIMM $\overline{\text{CAS}}$ latency is one clock less for Buffer mode.

^{2.} Access time is measured at 1.4V. See AC output load circuit.

^{3.} t_{CKH} is the pulse width of CLK measured from the positive edge to the negative edge referenced to V_{IH} (min). t_{CKL} is the pulse width of CLK measured from the negative edge to the positive edge referenced to V_{IL} (max).



Common Parameters

Coursells and	mbol Parameter		-2	60	-360		l laita	Notos	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units	Notes	
too	Commenced Cotton Time		2.0	_	2.0	_	ns	1 2	
t _{CS}	Command Setup Time	Buffered	7.7	_	7.7	_	ns	1, 2	
t	Command Hold Time	Registered	1.0	_	1.0	_	ns	1 2	
t _{CH}	Command Hold Time		0.0	_	0.0	_	ns	1, 2	
t	Address and Bank Select Setup Time	Registered	2.0	_	2.0	_	ns	1, 2	
t _{AS}	Address and Bank Select Setup Time	Buffered	7.7	_	7.7	_	— ns		
t	Address and Bank Select Hold Time	Registered	1.0	_	1.0	_	ns	1, 2	
t _{AH}	Address and bank Select Hold Time	Buffered	0.0	_	0.0	_	ns	1, 2	
t _{RCD}	RAS to CAS Delay		20	_	20	_	ns	1	
t _{RC}	Bank Cycle Time		70	_	70	_	ns	1	
t _{RAS}	Active Command Period		50	100000	50	100000	ns	1	
t _{RP}	Precharge Time		20	_	20	_	ns	1	
t _{RRD}	Bank to Bank Delay Time		20	_	20	_	ns	1	
t _{CCD}	CAS to CAS Delay Time (Same Bank)		1	_	1	_	CLK		

^{1.} These parameters account for the number of clock cycles and depend on the operating frequency of the clock as follows: the number of clock cycles = specified value of timing/clock period (count fractions as a whole number).

Mode Register Set Cycle

Symbol Parameter		-260		-360		Units	Notes
Symbol	Symbol Parameter	Min.	Max.	Min.	Max.	Units	Notes
t _{RSC}	Mode Register Set Cycle Time	2.0	_	2.0	_	CLK	1

^{1.} These parameters account for the number of clock cycles and depend on the operating frequency of the clock as follows: the number of clock cycles = specified value of timing/clock period (count fractions as a whole number).

^{2.} The set up and hold times refer to the addition of the register. Note that although the Buffered set up times appear much greater, there is no additional clock cycle as there is in Registered mode.



Refresh Cycle

Cymhal	Parameter	-260		-360		11-7-	Notes
Symbol	pol Parameter		Max.	Min.	Max.	Units	Notes
t _{REF}	Refresh Period	_	64	_	64	ms	1
1. 8192	cycles.						

Read Cycle

Combal		-260		-360		l laita	Nietes	
Symbol	Symbol Parameter		Min.	Max.	Min.	Max.	Units	Notes
t _{OH}	t _{OH} Data Out Hold Time		3.6	_	3.6	_	ns	
t_{LZ}	Data Out to Low Impedance Time		0.5	_	0.5	_	ns	
t _{HZ3}	Data Out to High Impedance Time		3.5	6.7	3.5	6.7	ns	1
t _{HZ2}	t _{HZ2} Data Out to High Impedance Time		3.5	6.7	3.5	6.7	ns	1
t	t DOM Data Out Disable Latency		3	_	3	_	CLK	
t _{DQZ} DQM Data Out	DQM Data Out Disable Latency	Buffered	2	_	2	_	CLK	

^{1.} Referenced to the time at which the output achieves the open circuit condition, not to output voltage levels.

Write Cycle

Symbol	Symbol Parameter		-260		-3	Units	
Symbol			Min.	Max.	Min.	Max.	Units
t _{DS}	Data In Setup Time		2.1	_	2.1	_	ns
t _{DH}	Data In Hold Time		1.6	_	1.6	_	ns
t	Data input to Dracharge	Registered	10	_	10	_	
t _{DPL}	t _{DPL} Data input to Precharge	Buffered	20		20		ns
4	Data lague to Active Cl. 2	Registered	4		4		
t _{DAL3}	Data Input to Active, CL = 3	Buffered	5		5		CLK
t	Data Input to Active CL = 2	Registered	4		4		CLK
t _{DAL2}	DAL2 Data Input to Active, CL = 2		5		5		
tnow	to DOM Write Mock Leteney		1	_	1	_	CLK
t _{DQW}	DQM Write Mask Latency	Buffered	0	_	0	_	CLK



Presence Detect Read and Write Cycle

Symbol	Parameter	Min.	Max.	Units	Notes
f_{SCL}	SCL Clock Frequency		100	kHZ	
T _I	Noise Suppression Time Constant at SCL, SDA Inputs		100	ns	
t _{AA}	SCL Low to SDA Data Out Valid	0.3	3.5	μs	
t _{BUF}	Time the Bus Must Be Free before a New Transmission Can Start	4.7		μs	
t _{HD:STA}	Start Condition Hold Time	4.0		μs	
t_{LOW}	Clock Low Period	4.7		μs	
t _{HIGH}	Clock High Period	4.0		μs	
t _{SU:STA}	Start Condition Setup Time (for a Repeated Start Condition)	4.7		μs	
t _{HD:DAT}	Data In Hold Time	0		μs	
t _{SU:DAT}	Data In Setup Time	250		ns	
t _r	SDA and SCL Rise Time		1	μs	
t _f	SDA and SCL Fall Time		300	ns	
t _{SU:STO}	Stop Condition Setup Time	4.7		μs	
t _{DH}	Data Out Hold Time	300		ns	
t_{WR}	Write Cycle Time		15	ms	1

The write cycle time (t_{WR}) is the time from a valid stop condition of a write sequence to the end of the internal erase/program cycle.
 During the write cycle, the bus interface circuits are disabled, SDA is allowed to remain high per the bus-level pullup resistor, and the device does not respond to its slave address.

Functional Description and Timing Diagrams

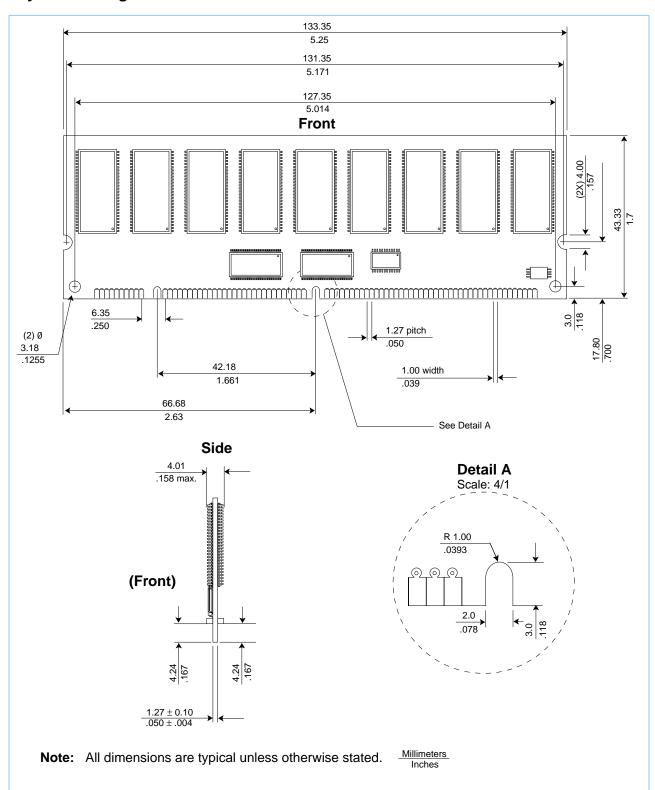
Refer to IBM 168 Pin SDRAM Registered DIMM Functional Description and Timing Diagrams (Document 01L5868) for registered-mode operation.

Refer to the IBM 256Mb Synchronous DRAM datasheet (Document 29L0000) for the functional description and timing diagrams for buffered-mode operation.

Refer to the IBM Application Notes *Serial Presence Detect on Memory DIMMs* and *SDRAM Presence Detect Definitions* for the Serial Presence Detect functional description and timings.



Layout Drawing







Revision Log

Rev	Contents of Modification
6/99	Initial release
2/00	Correct typo in package description



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